

Applications of Energetic Ion Beams at Surrey Ion Beam Centre



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Thanks to:

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and Roger Webb

Dr. Geoff Grime

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Natasha Clifton

Many ex-colleagues and external collaborators

Quality Assurance and Standards at Surrey Ion Beam Centre

- *Extensive QA program*
- *ISO9001 certified since 2008*
- Working with both NPL and PTB on various fundamental studies



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Surrey and Ion Beam

First van der Graaff accelerator
from Harwell was installed in
mid 1960s

New University, new
campus, new research team
and new research area

SRC, SERC, EPSRC and UKRI
supported national facility
from 1980s

Increasing demand for
irradiation of materials since
2000s



Ion – Solid Interaction

1. Ion **implantation**, the stopping of ions
2. Ion **irradiation**, lattice damage created
3. Ion Beam **Analysis**, ion induced effects
RBS, EBS, ERD, PIXE, PIGE, NRD
IBIL, IBIC, MeV-SIMS etc.

Perfect crystal is excellent, but crystals
with fully understood defects are even
better.

Surrey Ion Beam Centre: facility updates

- Broad beam: scanning of focused beam about 5 mm in beam spot size
 - 2 MV HVEE implanter, 200 kV to 2000 kV, over 36 years old
 - DF 1090 implanter, 1 kV to 200 kV, just 30 years old
 - 1.25 MV HVEE implanter, 90 kV to 1250 kV, new
- Focused beam: focused down to 20 nm level
 - SIMPLE 1 and SIMPLE 2, 25 kV
- IBA: 2 MV HVEE Tandem, 500 kV to 4000 kV
 - Broad beam RBS, PIXE, ERDA etc
 - Microbeam
 - TOF-ERDA
 - Super SIMS
 - External beam
- Sample processing and characterisation tools

Ions at Surrey Ion Beam Centre

Available Implanted Species

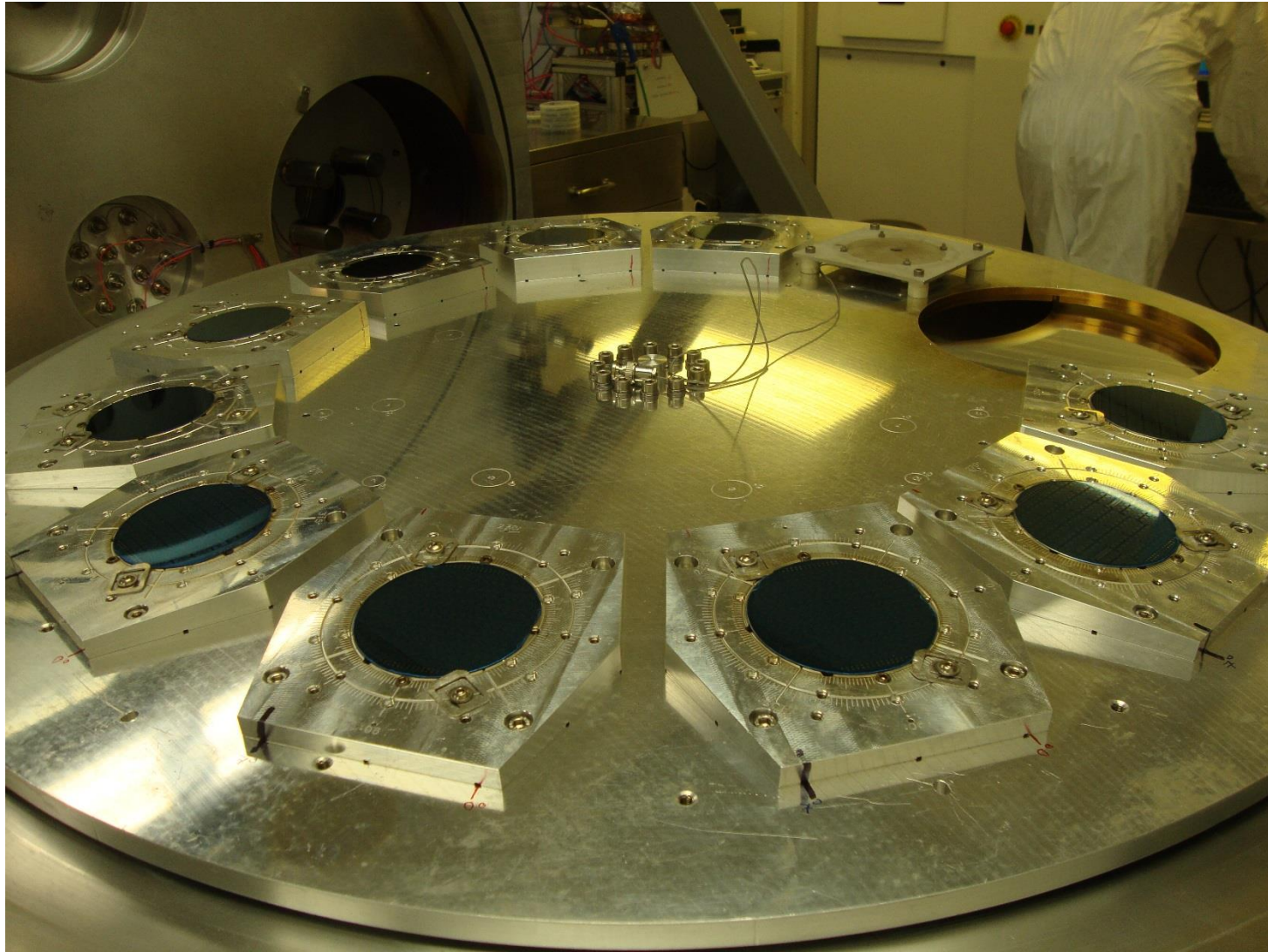
2 - 2000kV

Not Available

Call

H																	He
Li	Be											B	C	N	O	F	Ne
Na	Mg											Al	Si	P	S	Cl	Ar
K	Ca	Sc	Ti	V	Cr	Mn	Fe	Co	Ni	Cu	Zn	Ga	Ge	As	Se	Br	Kr
Rb	Sr	Y	Zr	Nb	Mo	Tc	Ru	Rh	Pd	Ag	Cd	In	Sn	Sb	Te	I	Xe
Cs	Ba	Lu	Hf	Ta	W	Re	Os	Ir	Pt	Au	Hg	Tl	Pb	Bi	Po	At	Rn
Fr	Ra	Lr	Rf	Db	Sg	Bh	Hs	Mt	Ds	Rg	Cn	Uut	Uuq	Uup	Uuh	Uus	Uuo
		La	Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb	Lu	
		Ac	Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No	Lw	

Sample stage for room temperature implant: carousel

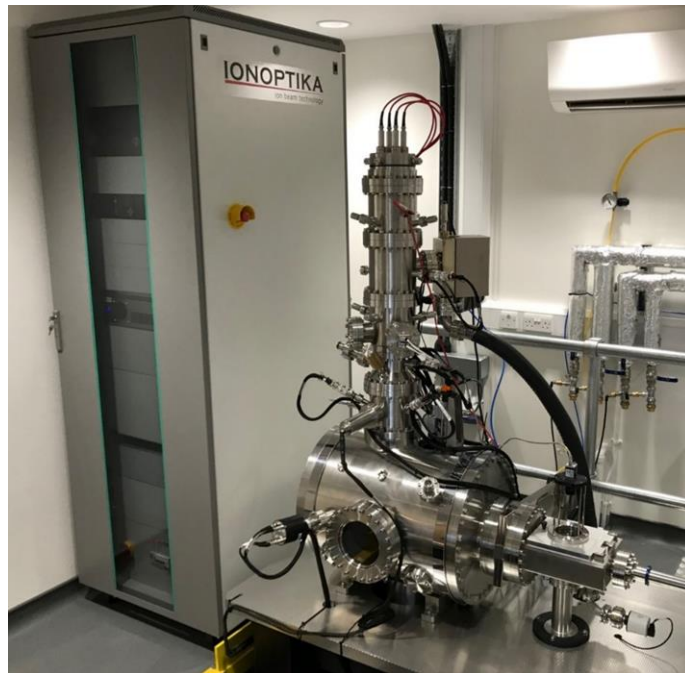


Applications of broad beam

Common materials modified with ion beams:

- Semiconductors: Si, InP, SiC, Ga₂O₃ etc.
 - Conductivity, refractive index
- Simulation of radiation effects
- Biomaterials
- Ceramic electrolytes for solid state battery
- Superconductors
- Smart cut: ion beam cut for making thin films

Applications of focused beam



Aim to support QT applications:

to be able to place **two atoms** such that they are **within 20nm** of each other.

Not one, and not three.

Repeat for a 100x100 array < 1hour

Capability	SIMPLE01
Ion species	Si, P, Mn, Se, Er, Bi, Ge...
Isotope selection	✓
Spatial resolution	<20 nm
Ion energy	5kV – 20kV
Deterministic doping	✓ (single ion)

Capability	SIMPLE02
Ion species	N, O, He, Ne, Ar...
Isotope selection	✓
Spatial resolution	<40 nm
Ion energy	5kV – 25kV
Deterministic doping	✓ (single ion)

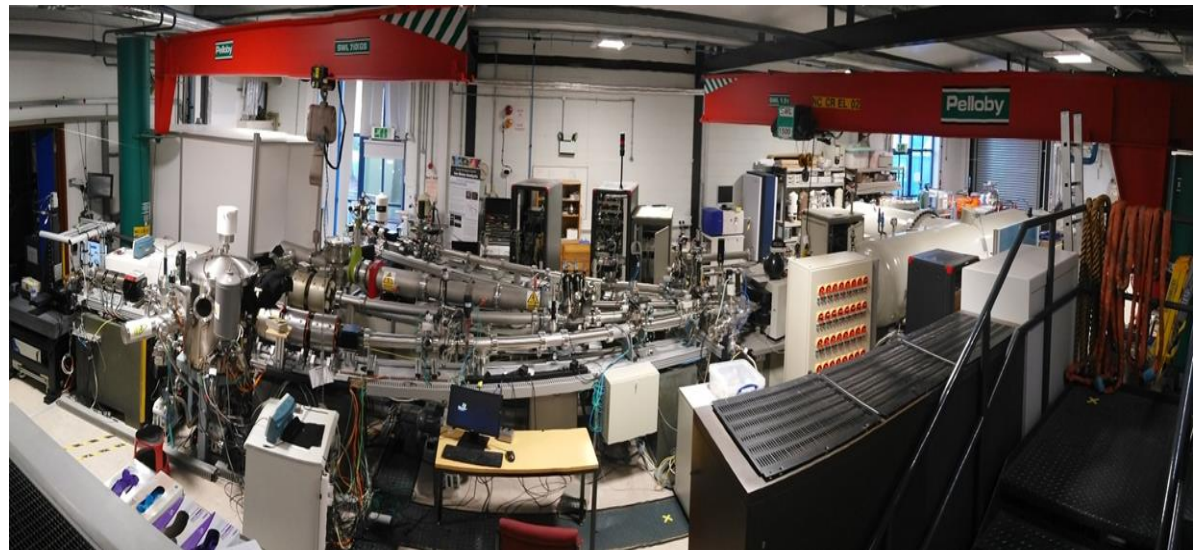
Low level ion implantation and irradiation for a small pre-selected area

Ion Beam Analysis

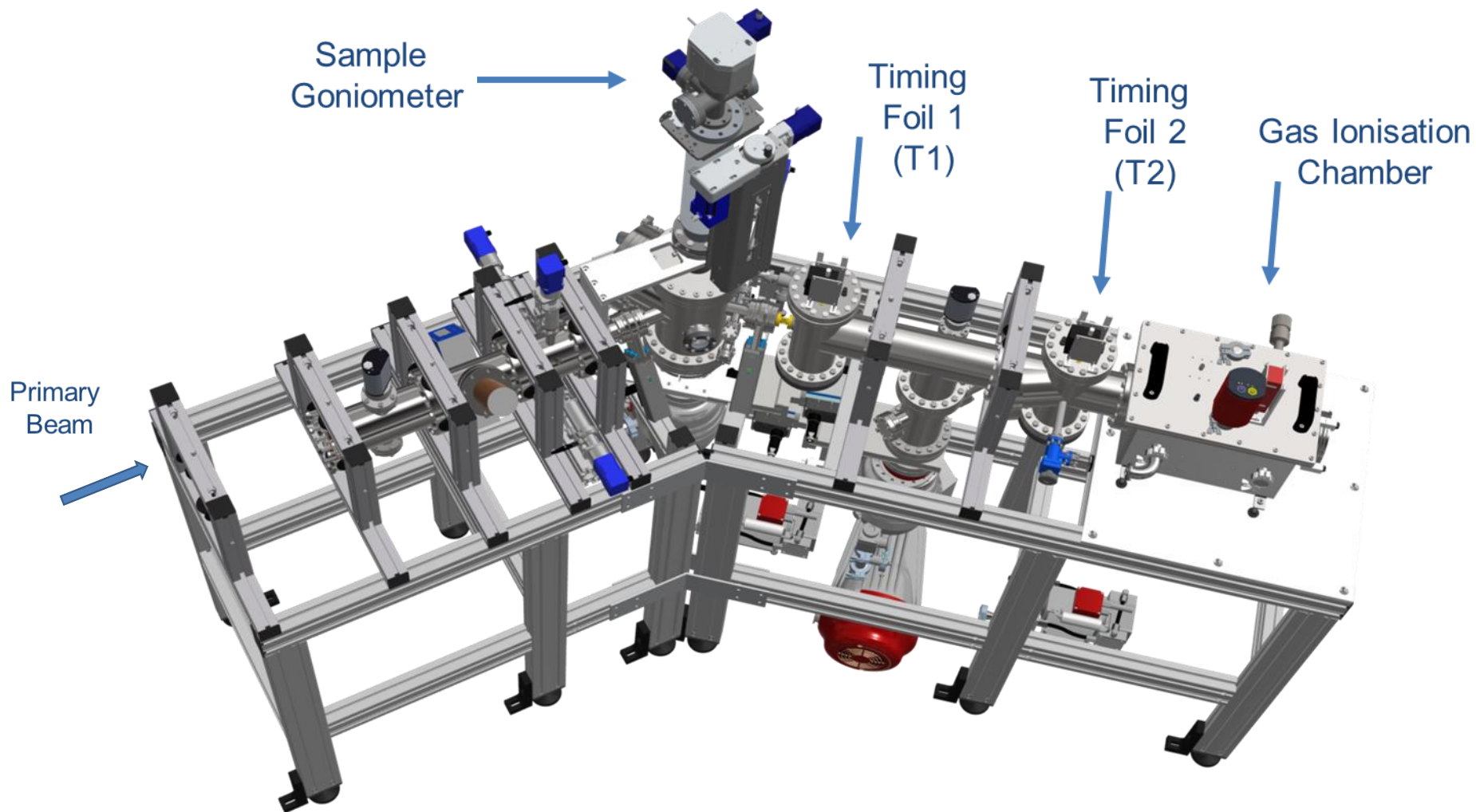
- **Advanced Materials Analysis**

- 2MV Tandem
- Techniques include RBS, ERD, PIXE, PIGE, NRA, IBIL, IBIC, MeV SIMS
- Channelling Spectroscopy for damage analysis
- Fully automated collection and analysis
- External Beam for vacuum sensitive samples ($\sim 2\mu\text{m}$)
- Horizontal nanobeam ($\sim 500\text{nm}$)
- Implantation line – heavy ion irradiation up to $\sim 10\text{MeV}$

Another reversed
engineering project:
derive original
chemical structures
(real space) from the
energy loss data
(momentum space)

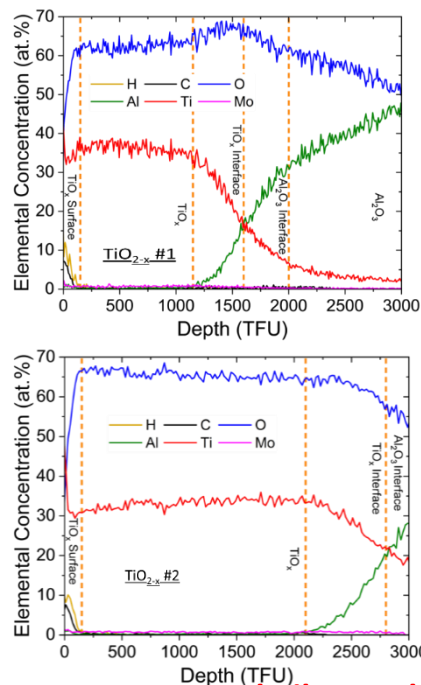
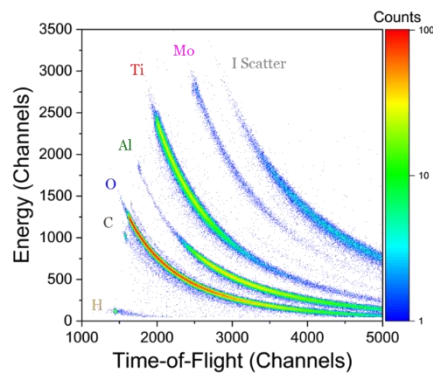


TOF-ERDA



Superconductors

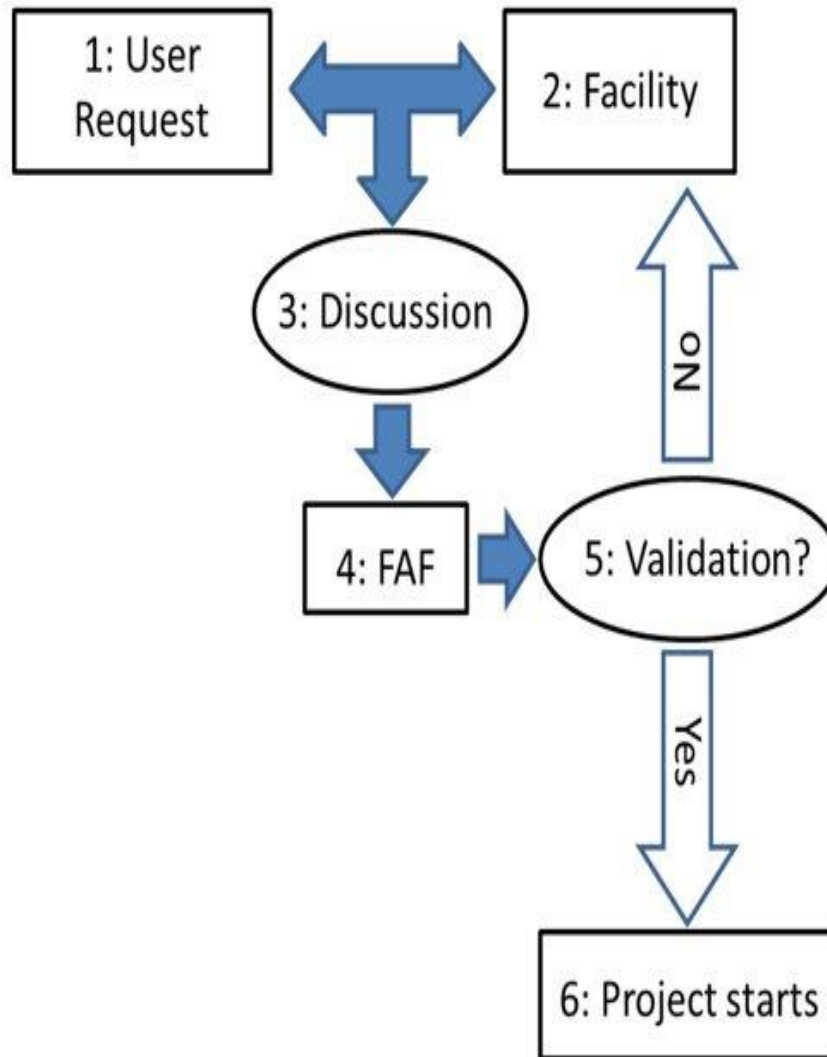
- Characterisation of oxygen concentration in superconducting TiO_{2-x} thin films



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Sample	O partial pressure /Pa	TiO_{2-x} thickness /nm	O/Ti ratio	Interface thickness /nm	O/Al ratio in Al_2O_3
TiO_{2-x} #1	4.7E-4	126	1.63	84	1.5
TiO_{2-x} #2	4.7E-4	223	1.95 – 1.55	Not fully visible	Not visible
TiO_{2-x} #3	1.0E-2	320 (not see full layer)	1.93	Not fully visible	Not visible
TiO_{2-x} #4	5.2E-4	145	1.88	146	1.47
TiO_{2-x} #5	5.2E-4	130	1.74 – 1.94	140	Not visible
TiO_{2-x} #6	7.0E-3	200	2.07	Not fully visible	Not visible

**How to get
access to our
facilities?**



Funding mechanisms:

There are four mechanisms through which users can gain access to our facilities:

New EPSRC Application – access is requested as part of an EPSRC application. If the grant is awarded then access will be automatically provided by the UKNIBC – we supply Technical Assessment (FAF) to go with your application.

Commercial - the user pays for the usage of each facility.

A proportion (25%) of UKNIBC time is earmarked for new projects that have no current EPSRC support for using ion beam facilities:

EPSRC Students - EPSRC funded students can access the UKNIBC in their own right.

Pump Priming and Existing EPSRC grants without beam time - access granted via a simple validation process.

For more detailed information, please visit our new website:

www.uknibc.co.uk

*Contact me via e-mail: n.peng@surrey.ac.uk
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Thank you for your attention!